Efficient Certified Defenses Against Patch Attacks on Image Classifiers

Ninth International Conference on Learning Representations, ICLR 2021

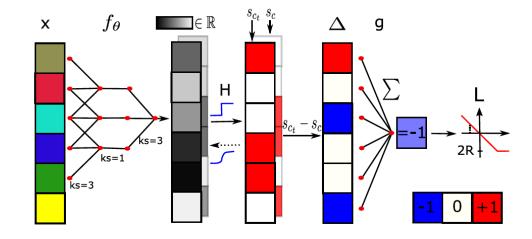
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Motivation

Adversarial patch threat model

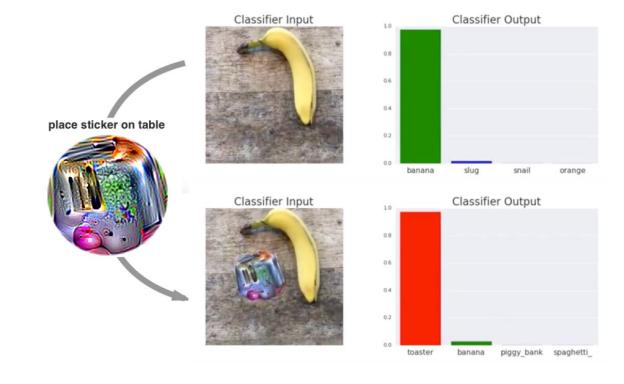


Image source: Brown et. al. Adversarial Patch, NeurIPS 2017



Motivation

- Adversarial patch threat model
- Physical world attacks on autonomous systems via their perception component

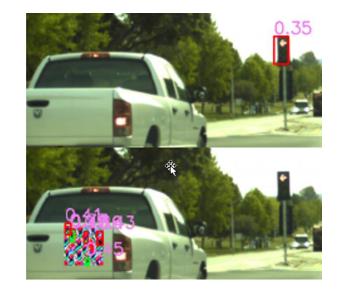


Image source: Metzen et. al. <u>Meta Adversarial Training</u>, 2021, https://arxiv.org/abs/2101.11453



Motivation

- Adversarial patch threat model
- Physical world attacks on autonomous systems via their perception component
- Safety-critical applications require a fail-safe fallback component with the following properties:
 - o certifiable robustness against patch attacks
 - efficient inference
 - o high performance on clean inputs

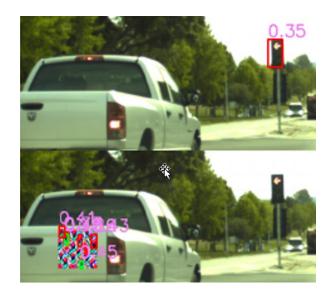
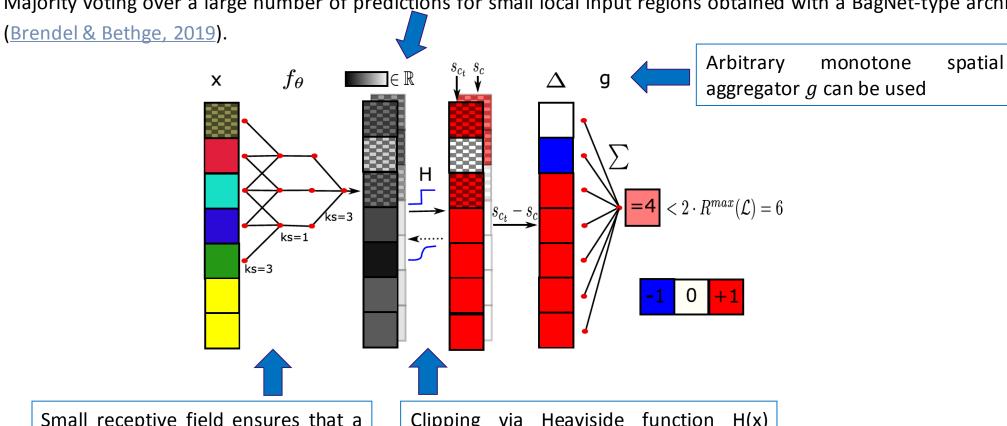


Image source: Metzen et. al. <u>Meta Adversarial Training</u>, 2021, https://arxiv.org/abs/2101.11453



BagCert: Architecture

Majority voting over a large number of predictions for small local input regions obtained with a BagNet-type architecture



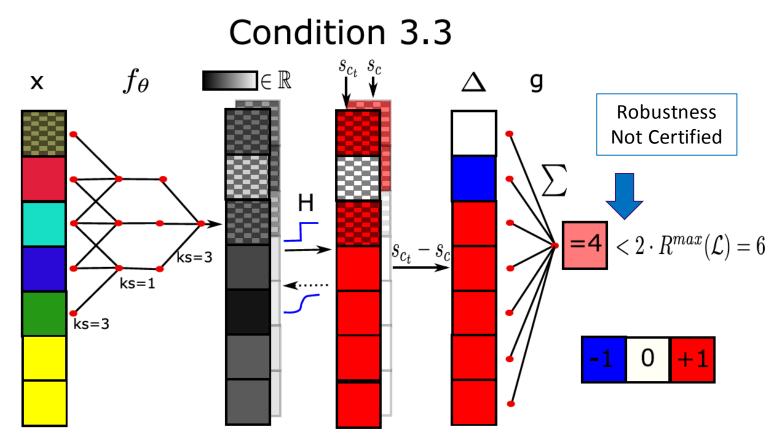
Small receptive field ensures that a local patch can only affect a small subset of predictions

Clipping via Heaviside function H(x)ensures that patches cannot increase individual scores arbitrarily



BagCert: Robustness Certification

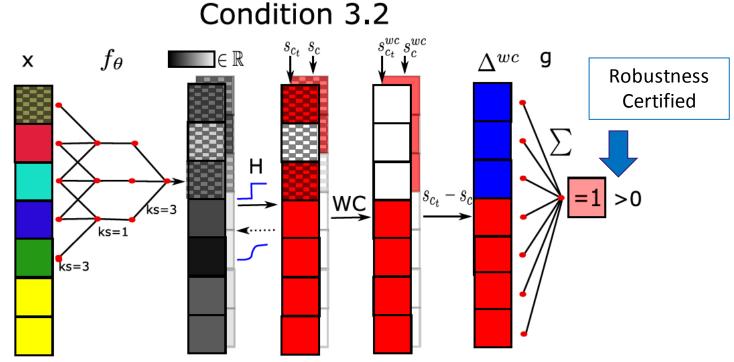
Our Certification Condition 3.3 corresponds to the one by proposed Levine & Feizi (2020)



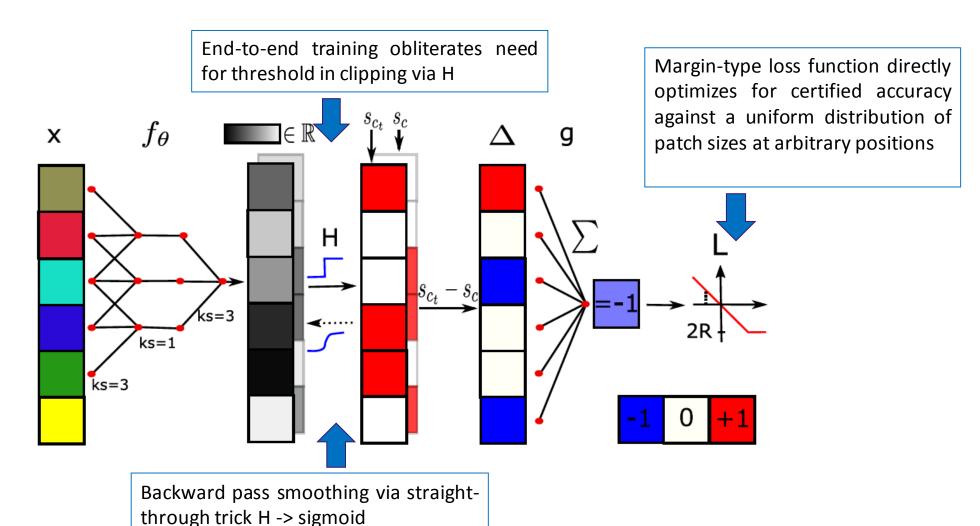
BagCert: Robustness Certification

Certification Condition 3.2 provides tighter bound: allows certifying robustness in more cases than previous work

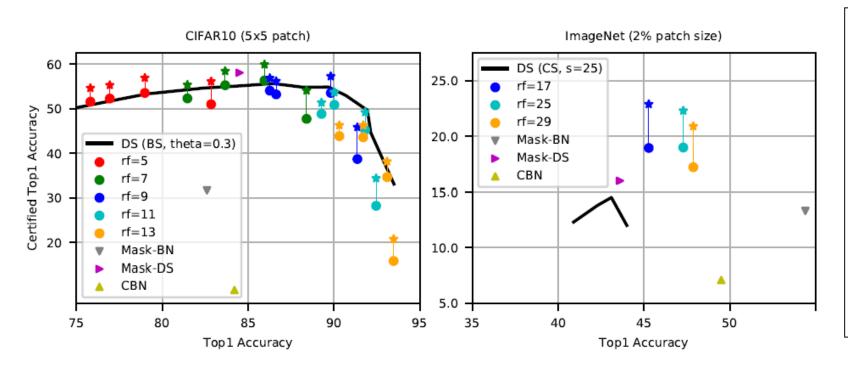
- improves certified accuracy of the same model by roughly 3 percent points on CIFAR-10.
- preferable if all score regions affected by patches are rectangular or if there is only moderate number of possible patch locations.



BagCert: End-to-end Training



Experimental Results: CIFAR10 and ImageNet



Plot legend:

Circles – certified via condition 3.3

Stars – certified via condition 3.2

DS – Derandomized smoothing **BS/CS** – batch/column smoothing (Levine & Feizi, 2020)

Mask-BN – Masked BagNet (Xiang et. al., 2020)

Mask-DS – Masked DS-ResNet (Xiang et. al., 2020)

CBN – Clipped BagNet

Zhang et. al., 2020

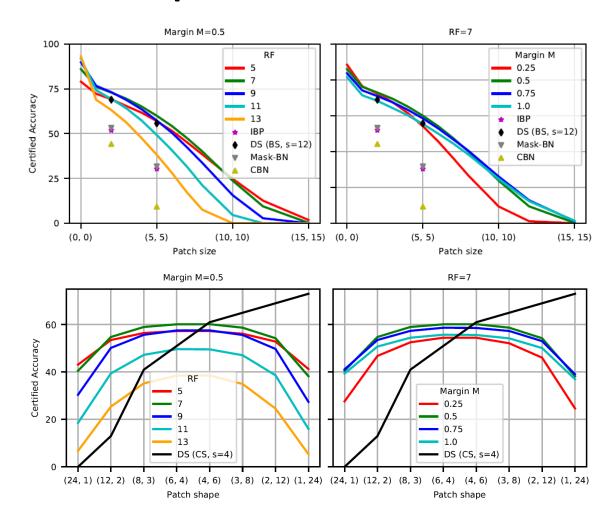
RF of BagCert	5	7	9	11	13	DS(BS)	DS(CS)
Cert. time (10.000 images)	39.0s	40.6s	43.2s	45.9s	48.5s	788.0s	28.0s
Number of parameters	28M	38M	57M	57M	66M	11M	11M



Experimental Results: Patch Sizes and Aspect Ratios

- A single configuration of BagCert (receptive field size 7, margin M=0.5) performs close to optimal for all patch sizes
 - can certify non-trivial performance for up to 10×10 patch size.

 BagCert has stable performance over different patch shapes unlike column smoothing proposed by <u>Levine &</u> <u>Feizi, 2020</u>.





BagCert and Derandomized smoothing (Levine & Feizi, 2020)

	Block Smoothing	Column/row Smoothing	BagCert
Efficient certification	No	Yes	Yes
Robustness against non-square patches	Yes	No	Yes

For more technical details, please visit our poster.

We are looking forward to the discussion!

